Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/807,636	CHEN ET AL.	
Examiner	Art Unit	
Nam Huynh	2617	

	SEAR	CHED	
Class	Subclass	Date	Examiner
See	Previous	10/27/2006	NTH
			- · · · -

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY)
	DATE	EXMR
See EAST search notes.	4/13/2007	NTH
· · · · · · · · · · · · · · · · · · ·		
·		